

Model: XD-300

Analytical Probe Station

>> The Probe Station XD-300

is a dedicated probing solution that comes with everything you need to achieve accurate measurement results in the shortest time, with maximum confidence. The system Provides best known methods for I-V/C-V measurements.

Designed for upgradability and extendable with multiple options. The Probe Station XD-300 can be easily reconfigured to meet your future project requirements, such as high voltage testing.

>> Specifications

Vacuum Chuck 12"

Huged-Knob Chuck Stage

Chuck stage 12"×12" Travel

Chuck Theta 0°~30°

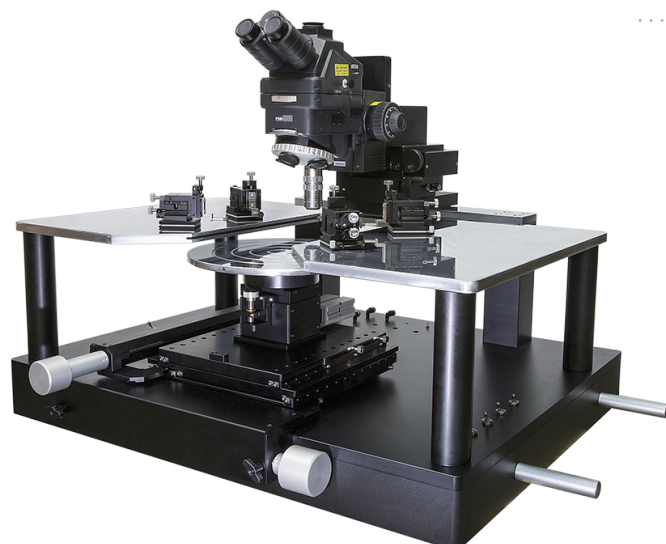
Microscope Stage 2"×2" Travel

Platen Up/Down 6mm Adjustable/Coarse Adjustment/Lever-Driven

Platen Up/Down 25mm Adjustable/Fine Adjustment/Hand wheel-Driven

920mmW x 660mmD x 700mmH With Microscope

Weight 180kg with microscope



>> Accessories

Microscope Magnification : 1000X

Hot Chuck : 200/300/400°C

Special Chuck Design for RF

Chuck Up/Down 4mm Adjustable

CCD and Screen

Micropositioner

Tip Holder

Shielding Box

Vibration Free Table